PAST TTTC EVENTS

**Nanotechnology Systems (DFT 2014)**
1–3 October 2014
Amsterdam, The Netherlands
http://www.dfts.org/

DFT is an annual Symposium providing an open forum for presentations in the field of defect and fault tolerance in VLSI systems inclusive of emerging technologies. One of the unique features of this symposium is to combine new academic research with state-of-the-art industrial data, necessary ingredients for significant advances in this field. All aspects of design, manufacturing, test, reliability, and availability that are affected by defects during manufacturing and by faults during system operation are of interest.

**IEEE International Workshop on Defects, Adaptive Test and Data Analysis (DATA 2014)**
23–24 October 2014
Seattle, WA, USA
http://data.tttc-events.org/

It’s all about the DATA. Everything we do in Test relies on data. We use data to identify our good parts, our bad parts, and our weak parts. We manipulate test data to detect outliers and reliability risks. We use data to control and adjust future testing. We also use data to record the full history of wafer lots and to track baseline production changes. And of course we have to collect all that data, store it, analyze it, secure it, and syndicate it to authorized consumers.

**5th IEEE International Workshop on Testing Three-Dimensional Stacked Integrated Circuits (3D-Test)**
23–24 October 2014
Seattle, WA, USA
http://3dtest.tttc-events.org/

The 3D-TEST Workshop focuses exclusively on test of and design-for-test for three-dimensional stacked ICs (3D-SICs), including Systems-in-Package (SiP), Package-on-Package (PoP), and especially 3D-SICs based on through-silicon vias (TSVs), micro-bumps, and/or interposers. While 3D-SICs offer many attractive advantages with respect to heterogeneous integration, smaller form-factor, higher bandwidth and performance, and lower power dissipation, there are many open issues with respect to testing such products. The 3D-TEST Workshop offers a forum to present and discuss these challenges and (emerging) solutions among researchers and practitioners alike.

**The 23rd Asian Test Symposium (AST 2014)**
16–19 November 2014
Hangzhou, China
http://ats2014.ict.ac.cn/dct/page/70004

The Asian Test Symposium (ATS) provides an open forum for researchers and industrial practitioners from all countries of the world, especially from Asia, to exchange innovative ideas on system, board, and device testing with design, manufacturing, and field consideration in mind.

UPCOMING TTTC EVENTS

**The 20th IEEE European Test Symposium (ETS 2015)**
Cluj-Napoca, Romania
http://www.ets15.ro/

The IEEE European Test Symposium (ETS) is Europe’s premier forum dedicated to presenting and discussing scientific results, emerging ideas, applications, hot topics, and new trends in the area of electronic-based circuits and system testing. In 2015, ETS will take place in the Cluj-Napoca, Romania. It is organized by the Technical University of Cluj-Napoca, which cosponsors the event jointly with the IEEE Council on Electronic Design Automation (CEDA).
ETS also features a special track on Emerging Test Strategies (ETS2), where new problems and ideas can be discussed in an informal atmosphere. ETS is the major event of the European Test Week that includes Test Spring School (TSS) from May 22 to 25, and three workshops from May 28 to 29.

Newsletter Editor’s Invitation

I would appreciate input and suggestions about the newsletter from the test community. Please forward your ideas, contributions, and information on awards, conferences, and workshops to Theocharis (Theo) Theocharides, Department of Electrical and Computer Engineering, University of Cyprus, 75 Kallipoleos Avenue, PO Box 20537, Nicosia, 1678, Cyprus; ttheocharides@ucy.ac.cy.

Theo Theocharides
Editor, TTTC Newsletter

CONTRIBUTIONS TO THIS NEWSLETTER: Send contributions to Theo Theocharides, Department of Electrical and Computer Engineering, University of Cyprus, 75 Kallipoleos Avenue, PO Box 20537, Nicosia 1678, Cyprus; ttheocharides@ucy.ac.cy http://tab.computer.org/tttc. For more information, see the TTTC Web page: http://tab.computer.org/tttc.